



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: Lawrence C. Gunn, III, *et al.* Attorney Docket No.: LUX-P038

Serial No.: 10/820,631

Group Art Unit: 2829

Filed: 4/7/2004

Examiner: Nguyen, Jimmy

Title: WAFER-LEVEL TESTING OF OPTICAL AND OPTOELECTRONIC CHIPS

AMENDMENT

The Commissioner of Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In Response to the Office action of November 16, 2005, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks begin on page 7 of this paper.

Conclusion begins on page 11 of this paper.